DS05-11149-1E

# MEMORY Unbuffered 8 M × 64 BIT SYNCHRONOUS DYNAMIC RAM DIMM

# MB8508S064CG-100/-100L

## 168-pin, 4 Clock, 1-bank, based on 8 M × 8 Bit SDRAMs with SPD

## **■** DESCRIPTION

The Fujitsu MB8508S064CG is a fully decoded, CMOS Synchronous Dynamic Random Access Memory (SDRAM) Module consisting of eight MB81F64842C devices which organized as four banks of 8 M  $\times$  8 bits and a 2K-bit serial EEPROM on a 168-pin glass-epoxy substrate.

The MB8508S064CG features a fully synchronous operation referenced to a positive edge clock whereby all operations are synchronized at a clock input which enables high performance and simple user interface coexistence.

The MB8508S064CG is optimized for those applications requiring high speed, high performance and large memory storage, and high density memory organizations.

This module is ideally suited for workstations, PCs, laser printers, and other applications where a simple interface is needed.

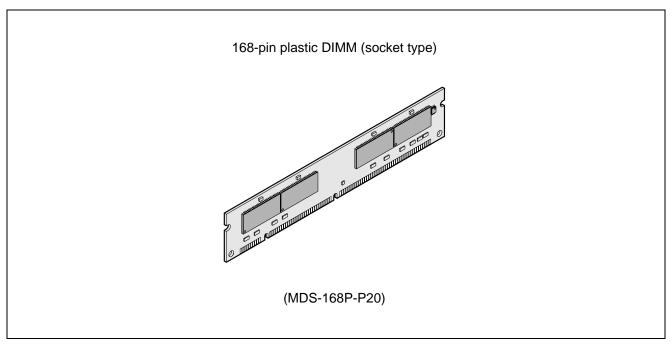
#### **■ PRODUCT LINE & FEATURES**

Parameter	MB8508	S064CG		
Farameter	-100	-100L		
Clock Frequency	100 MF	Hz max.		
Burst Mode Cycle Time	10 ns	s min.		
Access Time from Clock	8.5 ns ma:	x. (CL = 3)		
Operating Current	680 m	A max.		
Power Down Mode Current (Icc2P)	16 mA max.	8 mA max.		
Self Refresh Current (Iccs)	8 mA max.	4 mA max.		

- Unbuffered 168-pin DIMM Socket Type (Lead pitch: 1.27 mm)
- Conformed to JEDEC Standard (4 CLK)
- Organization: 8,388,608 words × 64 bits
- Memory: MB81F64842C (8 M × 8, 4-bank) × 8 pcs.
- 3.3 V ±0.3 V Supply Voltage
- All input/output LVTTL compatible
- 4096 Refresh Cycle every 65.6 ms

- · Auto and Self Refresh
- CKE Power Down Mode
- DQM Byte Masking (Read/Write)
- Serial Presence Detect (SPD) with Serial EEPROM: JEDEC Standard SPD Format
- Module size:
  - 1.0" (height)  $\times$  5.25" (length)  $\times$  0.157" (thickness)
- CL-trcd-trp: 3-3-3 clk min. @100 MHz,
   2-2-2 clk min. @66 MHz

## **■ PACKAGE**

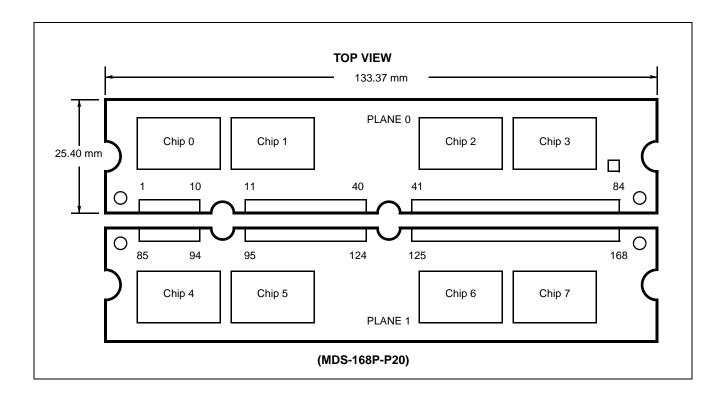


## **Package and Ordering Information**

168-pin DIMM, order as MB8508S064CG-100DG (DG = Gold Pad)
 MB8508S064CG-100LDG (LDG = Low power ver., Gold Pad)

## **■ PIN ASSIGNMENTS**

Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name
1	Vss	29	DQMB <sub>1</sub>	57	DQ <sub>18</sub>	85	Vss	113	DQMB₅	141	DQ <sub>50</sub>
2	DQ₀	30	<del>CS</del> ₀	58	DQ <sub>19</sub>	86	DQ <sub>32</sub>	114	N.C.	142	DQ <sub>51</sub>
3	DQ <sub>1</sub>	31	N.C.	59	Vcc	87	DQ <sub>33</sub>	115	RAS	143	Vcc
4	DQ <sub>2</sub>	32	Vss	60	DQ <sub>20</sub>	88	DQ <sub>34</sub>	116	Vss	144	DQ <sub>52</sub>
5	DQ <sub>3</sub>	33	A <sub>0</sub>	61	N.C.	89	DQ <sub>35</sub>	117	A <sub>1</sub>	145	N.C.
6	Vcc	34	A <sub>2</sub>	62	N.C.	90	Vcc	118	<b>A</b> 3	146	N.C.
7	DQ <sub>4</sub>	35	A <sub>4</sub>	63	N.C.	91	DQ <sub>36</sub>	119	<b>A</b> 5	147	N.C.
8	DQ₅	36	<b>A</b> 6	64	Vss	92	DQ <sub>37</sub>	120	A <sub>7</sub>	148	Vss
9	DQ <sub>6</sub>	37	A8	65	DQ <sub>21</sub>	93	DQ <sub>38</sub>	121	<b>A</b> 9	149	DQ <sub>53</sub>
10	DQ <sub>7</sub>	38	A <sub>10</sub>	66	DQ <sub>22</sub>	94	DQ <sub>39</sub>	122	BA <sub>0</sub>	150	DQ <sub>54</sub>
11	DQ <sub>8</sub>	39	BA <sub>1</sub>	67	DQ <sub>23</sub>	95	DQ <sub>40</sub>	123	A <sub>11</sub>	151	DQ <sub>55</sub>
12	Vss	40	Vcc	68	Vss	96	Vss	124	Vcc	152	Vss
13	DQ <sub>9</sub>	41	Vcc	69	DQ <sub>24</sub>	97	DQ <sub>41</sub>	125	CLK <sub>1</sub>	153	DQ <sub>56</sub>
14	DQ <sub>10</sub>	42	CLK <sub>0</sub>	70	DQ <sub>25</sub>	98	DQ <sub>42</sub>	126	N.C.	154	DQ <sub>57</sub>
15	DQ <sub>11</sub>	43	Vss	71	DQ <sub>26</sub>	99	DQ <sub>43</sub>	127	Vss	155	DQ <sub>58</sub>
16	DQ <sub>12</sub>	44	N.C.	72	DQ <sub>27</sub>	100	DQ <sub>44</sub>	128	CKE <sub>0</sub>	156	DQ <sub>59</sub>
17	DQ <sub>13</sub>	45	$\overline{\text{CS}}_2$	73	Vcc	101	DQ <sub>45</sub>	129	N.C.	157	Vcc
18	Vcc	46	DQMB <sub>2</sub>	74	DQ <sub>28</sub>	102	Vcc	130	DQMB <sub>6</sub>	158	DQ <sub>60</sub>
19	DQ <sub>14</sub>	47	DQMB <sub>3</sub>	75	DQ <sub>29</sub>	103	DQ <sub>46</sub>	131	DQMB <sub>7</sub>	159	DQ <sub>61</sub>
20	DQ <sub>15</sub>	48	N.C.	76	DQ <sub>30</sub>	104	DQ <sub>47</sub>	132	N.C.	160	DQ <sub>62</sub>
21	N.C.	49	Vcc	77	DQ <sub>31</sub>	105	N.C.	133	Vcc	161	DQ <sub>63</sub>
22	N.C.	50	N.C.	78	Vss	106	N.C.	134	N.C.	162	Vss
23	Vss	51	N.C.	79	CLK <sub>2</sub>	107	Vss	135	N.C.	163	CLK <sub>3</sub>
24	N.C.	52	N.C.	80	N.C.	108	N.C.	136	N.C.	164	N.C.
25	N.C.	53	N.C.	81	N.C.	109	N.C.	137	N.C.	165	SA <sub>0</sub>
26	Vcc	54	Vss	82	SDA	110	Vcc	138	Vss	166	SA <sub>1</sub>
27	WE	55	DQ <sub>16</sub>	83	SCL	111	CAS	139	DQ <sub>48</sub>	167	SA <sub>2</sub>
28	DQMB <sub>0</sub>	56	DQ <sub>17</sub>	84	Vcc	112	DQMB <sub>4</sub>	140	DQ <sub>49</sub>	168	Vcc



## **■ PIN DESCRIPTIONS**

Symbol	I/O	Function	Symbol	I/O	Function
A <sub>0</sub> to A <sub>11</sub> , BA <sub>0</sub> , BA <sub>1</sub>	I	Address Input	DQ <sub>0</sub> to DQ <sub>63</sub>	I/O	Data Input/Data Output
RAS	I	Row Address Strobe	Vcc	_	Power Supply (+3.3 V)
CAS	I	Column Address Strobe	Vss	_	Ground (0 V)
WE	I	Write Enable	N.C.	_	No Connection
DQMB <sub>0</sub> to DQMB <sub>7</sub>	I	Data (DQ) Mask	SA <sub>0</sub> to SA <sub>2</sub>	I	Serial PD Address Input
CLK₀ to CLK₃	I	Clock Input	SCL	I	Serial PD Clock
CKE₀	I	Clock Enable	SDA	I/O	Serial PD Address/Data Input/Output
$\overline{\text{CS}}_0, \overline{\text{CS}}_2$	I	Chip Select			

## ■ SERIAL-PD INFORMATION

D. rto	Function Described		Hex Value
Byte	Function Described		-100/100L
0	Defines Number of Bytes Written into	128 Byte	80h
	Serial Memory at Module Manufacture		
1	Total Number of Bytes of SPD Memory Device	256 Byte	08h
2 3	Fundamental Memory Type	SDRAM	04h
	Number of Row Addresses	12	0Ch
4	Number of Column Addresses	9	09h
5	Number of Module Banks	1 bank	01h
6	Data Width	64 bit	40h
7	Data Width (Continuation)	+0	00h
8	Interface Type	LVTTL	01h
9	SDRAM Cycle Time (Highest CAS Latency)	10 ns	A0h
10	SDRAM Access from Clock (Highest CAS Latency)	8.5 ns	85h
11	DIMM Configuration Type	Non-Parity	00h
12	Refresh Rate/Type	Self, Normal	80h
13	Primary SDRAM Width	×8	08h
14	Error Checking SDRAM Width	0	00h
15	Minimum Clock Delay for Back to Back Random Column	1 Cycle	01h
	Addresses	, , ,	-
16	Burst Lengths Supported	1, 2, 4, 8, Page	8Fh
17	Number of Banks on Each SDRAM Device	4 bank	04h
18	CAS Latency	2, 3	06h
19	CS Latency	0	01h
20	Write Latency	0	01h
21	SDRAM Module Attributes	UN-buffer	00h
22	SDRAM Device Attributes	*1	0Eh
23	SDRAM Cycle Time (2nd. Highest CAS Latency)	15 ns	F0h
24	SDRAM Access from Clock (2nd. Highest CAS Latency)	9 ns	90h
25	SDRAM Cycle Time (3rd. Highest CAS Latency)	No Support	00h
26	SDRAM Access from Clock (3rd. Highest CAS Latency)	No Support	00h
27	Minimum Row Precharge Time (tra)	30 ns	1Eh
28	Row Activate to Row Activate Min. (trrd)	20 ns	14h
29	RAS to CAS Delay Min. (trcb)	30 ns	1Eh
30	Minimum RAS Pulse Width	60 ns	3Ch
31	Module Bank Density	64 MByte	10h
32 to 61	Unused Storage Locations	— —	00h
62	SPD Data Revision Code	1	01h
63	Checksum for Byte 0 to 62	*2	57h
64 to 98	Manufacturer's Information: Unused Storage		00h
99 to 125	Vendor Specific Data: Unused Storage	_	00h
126	Intel specification Frequency	66MHz	66h
127	Intel specification Details for 66MHz Support	CL=2, 3	CFh
128+	Unused Storage Locations		
120+	onuscu otorage Locations	_	<del></del>

**Note:** Any write operation must NOT be executed into the addresses of Byte 0 to Byte 127. Some or all data stored into Byte 0 to Byte 127 may be broken.

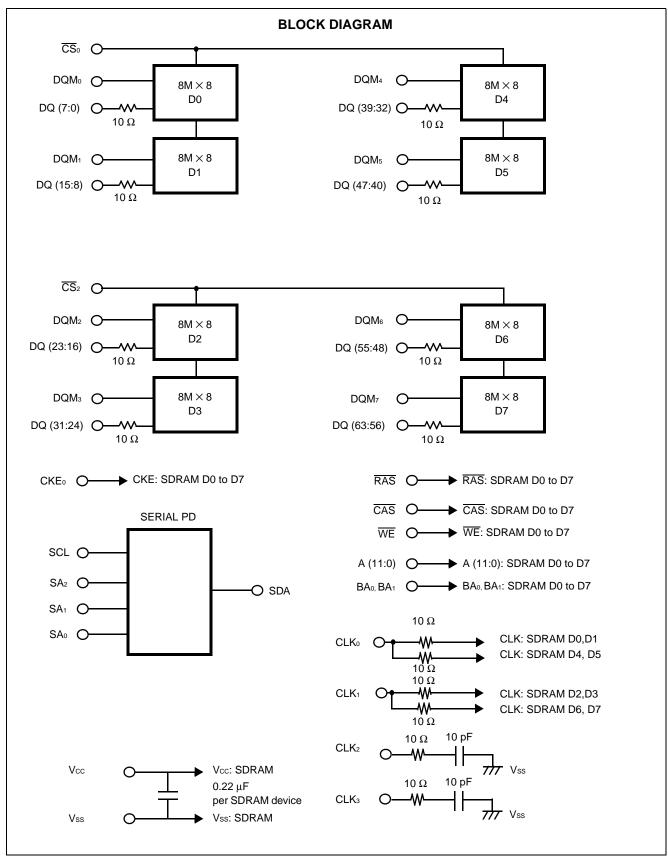
## \*1. Byte 22: SDRAM Device Attributes

Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	Bit0
TBD	TBD	Upper Vcc tolerance	Lower Vcc tolerance	Supports Write 1 /Read Burst	Supports Precharge All	Supports Auto- precharge	Supports Early RAS Precharge
0	0	0	0	1	1	1	0

<sup>\*2.</sup> Byte 63: Checksum for Bytes 0 to 62

This byte is the checksum for bytes 0 through 62. This byte contains the value of the low 8-bits of the arithmetic sum of bytes 0 through 62.

## **■ BLOCK DIAGRAM**



## ■ ABSOLUTE MAXIMUM RATINGS (See WARNING)

Parameter	Symbol	Va	Unit		
Farameter	Symbol	Min.	Max.	Offic	
Supply Voltage*	Vcc	-0.5	+4.6	V	
Input Voltage*	Vin	-0.5	+4.6	V	
Output Voltage*	Vоит	-0.5	+4.6	V	
Storage Temperature	Тѕтс	<b>–</b> 55	+125	°C	
Power Dissipation	P <sub>D</sub>	_	8.0	W	
Output Current (D.C.)	Іоит	-50	+50	mA	

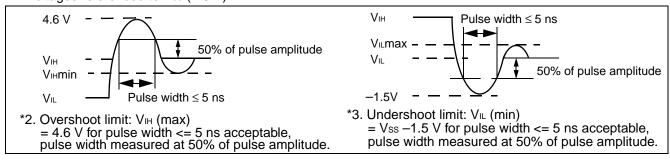
<sup>\*:</sup> Voltages referenced to Vss (= 0 V)

**WARNING:** Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

## ■ RECOMMENDED OPERATING CONDITIONS

Doromotor	Notes	Symbol		Unit		
Parameter	Notes		Min.	Тур.	Max.	Unit
Cumply Voltage	*1	Vcc	3.0	3.3	3.6	V
Supply Voltage	Į.	Vss	0	0	0	V
Input High Voltage, All Inputs	*1, 2	ViH	2.0	_	Vcc +0.5	V
Input Low Voltage, All Inputs	*1, 3	VIL	-0.5	_	0.8	V
Ambient Temperature		TA	0	_	+70	°C

## \*1. Voltages referenced to Vss (= 0 V)



**WARNING:** The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating conditionranges. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

## **■ CAPACITANCE**

(Vcc = +3.3 V, f = 1 MHz,  $T_A = +25$ °C)

Poromoi	Parameter  A <sub>0</sub> to A <sub>11</sub> , BA <sub>0</sub> , BA <sub>1</sub> RAS, CAS, WE  CS <sub>0</sub> , CS <sub>2</sub>	Symbol	Va	Unit	
Paramet	lei	Symbol	Min.	Value       Min.     Max.       —     67       —     56       —     32       —     58       —     41       —     17       —     7       —     9       —     8       —     13	- Offic
	A <sub>0</sub> to A <sub>11</sub> , BA <sub>0</sub> , BA <sub>1</sub>	C <sub>IN1</sub>	_	67	pF
	RAS, CAS, WE	C <sub>IN2</sub>	_	56	pF
	$\overline{\text{CS}}_0, \overline{\text{CS}}_2$	C <sub>IN3</sub>	_	32	pF
Input Conscitones	CKE <sub>0</sub>	C <sub>IN4</sub>	_	58	pF
Input Capacitance	CLK <sub>0</sub> to CLK <sub>3</sub>	C <sub>IN5</sub>	_	41	pF
	DQMB <sub>0</sub> to DQMB <sub>7</sub>	CIN6	_	17	pF
	SCL	Cscl	_	7	pF
	SA <sub>0</sub> , SA <sub>1</sub> , SA <sub>2</sub>	Csa	_	9	pF
Input/Output Capacitance	SDA	CSDA	_	8	pF
Input/Output Capacitance	DQ <sub>0</sub> to DQ <sub>63</sub>	CDQ	_	13	pF

## **■ DC CHARACTERISTICS**

(At recommended operating conditions unless otherwise noted.) Notes 1, 2

Parameter Notes Symbol Condi			Value				
Parameter	Notes	Symbol	Condition	Min.	M	ax.	Unit
				IVIIII.	Std. ver.	Low ver.	
Operating Current (Average Power Supply Current)	*3	Icc1s	Burst: Length = 1 tRC = min for $BL = 1tCK = minOne Bank Active, Outputs OpenAddresses changed up to 1-timeduring tCK (min.)0 \ V \le V_{IN} \le V_{IL} (max.)V_{IH} (min.) \le V_{IN} \le V_{CC}$	_	6	80	mA
		Ісс2Р	CKE = $V_{IL}$ , All Banks Idle tck = min, Power Down Mode $0 \ V \le V_{IN} \le V_{IL}$ (max.) $V_{IH}$ (min.) $\le V_{IN} \le V_{CC}$	_	16	8	mA
Precharge Standby Current (Power Supply Current)  *3 $I_{CC2PS}$ *3 $I_{CC2PS}$ CKE = V <sub>IL</sub> , All Bar CLK = H or L, Power VIH (min.) $\leq$ VIN $\leq$ VIL (max VIH (min.)) $\leq$ VIN $\leq$ VIN $\leq$ VIH, All Bar NOP commands (except to CMD) aduring 3 clock cycle (except to CMD) aduring 3 clock cycle (except to CMD) $\leq$ VIN $\leq$		Icc2PS	CKE = $V_{IL}$ , All Banks Idle CLK = H or L, Power Down Mode 0 V $\leq$ V <sub>IN</sub> $\leq$ V <sub>IL</sub> (max.) V <sub>IH</sub> (min.) $\leq$ V <sub>IN</sub> $\leq$ V <sub>CC</sub>	_	8	4	mA
	CKE = $V_{IH}$ , All Banks Idle, $t_{CK}$ = min NOP commands only, Input signals (except to CMD) are changed 1-time during 3 clock cycles $0 \text{ V} \leq V_{IN} \leq V_{IL}$ (max.) $V_{IH}$ (min.) $\leq V_{IN} \leq V_{CC}$	_	80		mA		
		Icc2ns	CKE = $V_{IH}$ , All Banks Idle CLK = H or L, Input signal are stable 0 V $\leq$ V <sub>IN</sub> $\leq$ V <sub>IL</sub> (max.) V <sub>IH</sub> (min.) $\leq$ V <sub>IN</sub> $\leq$ V <sub>CC</sub>	_	1	4	mA
		Іссзр	CKE = $V_{IL}$ , Any Bank Active tck = min. 0 V $\leq$ V <sub>IN</sub> $\leq$ V <sub>IL</sub> (max.) V <sub>IH</sub> (min.) $\leq$ V <sub>IN</sub> $\leq$ V <sub>CC</sub>	_	16	16	mA
Active Standby		Іссзрѕ	CKE = $V_{IL}$ , Any Bank Active CLK = H or L 0 V $\leq$ V <sub>IN</sub> $\leq$ V <sub>IL</sub> (max.) V <sub>IH</sub> (min.) $\leq$ V <sub>IN</sub> $\leq$ V <sub>CC</sub>	_	8	4	mA
Active Standby Current (Power Supply Current)	*3	Іссэн	CKE = $V_{IH}$ , Any Bank Active tck = min., NOP commands only, Input signals (except to CMD) are changed 1-time during 3 clock cycles $0 \text{ V} \leq V_{IN} \leq V_{IL}$ (max.) $V_{IH}$ (min.) $\leq V_{IN} \leq V_{CC}$	_	1:	20	mA
		Іссзиѕ	CKE = V <sub>IH</sub> , Any Bank Active CLK = H or L $0 \text{ V} \le \text{V}_{\text{IN}} \le \text{V}_{\text{IL}} \text{ (max.)}$ V <sub>IH</sub> (min.) $\le \text{V}_{\text{IN}} \le \text{V}_{\text{CC}}$	_	1	6	mA

(Continued)

## (Continued)

Parameter I	Notes	Symbol	Condition	Min	Max.		Unit
				Min.	Low ver.		
Burst Mode Current (Average Power Supply Current)	*3	Icc4	tck = min, Burst Length = 4 Outputs Open, All Banks Active Gapless Data $0 \ V \le V_{IN} \le V_{IL}$ (max.) $V_{IH}$ (min.) $\le V_{IN} \le V_{CC}$	_	48	30	mA
Auto-refresh Current (Average Power Supply Current)	*3	Icc5	Auto Refresh tck = min trc = min $0 \text{ V} \leq V_{IN} \leq V_{IL} \text{ (max.)}$ Vih (min.) $\leq V_{IN} \leq V_{CC}$	_	13	60	mA
Self-refresh Current (Average Power Supply Current)	*3	Icc <sub>6</sub>		_	8	4	mA
Input Leakage Current (All Inputs)		lı (L)	$0 \text{ V} \le V_{\text{IN}} \le V_{\text{CC}}$ All other pins not under test = $0 \text{ V}$	-30	3	0	μΑ
Output Leakage Currer	nt	lo (L)	$0 \text{ V} \le V_{IN} \le V_{CC}$ Output is disabled (Hi-Z)	-10	1	0	μΑ
LVTTL Output High Voltage	*4	Vон	Iон = −2.0 mA	2.4	_	_	V
LVTTL Output Low Voltage	*4	Vol	loL = +2.0 mA	_	0	.4	V

**Notes:** \*1. An initial pause (DESL on NOP) of 200 μs is required after power-on followed by a minimum of eight Auto-refresh cycles.

<sup>\*2.</sup> DC characteristics is the Serial PD standby state (V<sub>IN</sub> = V<sub>SS</sub> or V<sub>CC</sub>).

<sup>\*3.</sup> lcc depends on the output termination, load conditions, clock cycle rate and signal clock rate. The specified values are obtained with the output open and no termination register.

<sup>\*4.</sup> Voltages referenced to Vss = Vssq (= 0 V).

## **■ AC CHARACTERISTICS**

## (1) BASE CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.) Notes 1, 2, 3

No.	Parameter Notes	Notes		MB8508S064CG -100/100L		Unit
			Symbol	Min.	Max.	
1	Clock Period	CL = 3	<b>t</b> cкз	10	_	ns
'	Clock Feriod	CL = 2	<b>t</b> ck2	15	_	ns
2	Clock High Time		tсн	3.5	_	ns
3	Clock Low Time		<b>t</b> cL	3.5	_	ns
4	Input Setup Time		<b>t</b> sı	3	_	ns
5	Input Hold Time		tнı	1	_	ns
6	Output Valid from Clock	CL = 3	t <sub>AC3</sub>	_	8.5	ns
	(tclk = min)	CL = 2	t <sub>AC2</sub>	_	9	115
7	Output in Low-Z *6	}	<b>t</b> LZ	0	_	ns
8	Output in High-Z *6	CL = 3	<b>t</b> HZ3	3	8.5	ns
0	Output in riign-2	CL = 2	t <sub>HZ2</sub>	3	9	ns
9	Output Hold Time *6	, ,	tон	3	_	ns
10	Time between Refresh		tref	_	65.6	ms
11	Transition Time		tτ	0.5	2	ns
12	CKE Setup Time for Power Down Exit Time	)	<b>t</b> CKSP	3	_	ns

## (2) BASE VALUES FOR CLOCK COUNT/LATENCY

No.	Parameter Notes		Symbol	MB8508 -100/	Unit		
				Min.	Max.		
1	RAS Cycle Time *7		<b>t</b> RC	90	_	ns	
2	RAS Precharge Time		<b>t</b> RP	30	_	ns	
3	RAS Active Time	<b>t</b> ras	60	110000	ns		
4	RAS to CAS Delay Time *8	<b>t</b> RCD	30	_	ns		
5	Write Recovery Time		twR	10	_	ns	
6	RAS to RAS Bank Active Delay Time		<b>t</b> rrd	20	_	ns	
7	Data-in to Precharge Lead Time		<b>t</b> DPL	10	_	ns	
8	Data-in to Active/Refresh Command Period	CL = 3	<b>t</b> DAL3	2 cyc + t <sub>RP</sub>	_	ns	
8	Data-in to Active/Refresh Command Period	CL = 2	tDAL2	1 cyc + t <sub>RP</sub>	_	ns	
9	Mode Register Set Cycle Time		<b>t</b> RSC	20	_	ns	

## (3) CLOCK COUNT FORMULA (\*9)

$$Clock \ge \frac{Base\ Value}{Clock\ Period}\ (Round\ off\ a\ whole\ number)$$

## (4) LATENCY (The latency values on these parameters are fixed regardless of clock period.)

No.	Parameter		Symbol	MB8508S064CG -100/100L	Unit
1	CKE to Clock Disable		Іске	1	Cycle
2	DQM to Output in High-Z		IDQZ	2	Cycle
3	DQM to Input Data Delay		IDQD	0	Cycle
4	Last Output to Write Command Delay		lowd	2	Cycle
5	Write Command to Input Data Delay		Idwd	0	Cycle
6	Dracharge to Output in High 7 Delev	CL = 3	Ігонз	3	Cycle
0	Precharge to Output in High-Z Delay	CL = 2	I <sub>ROH2</sub>	2	Cycle
7	Durat Stan Command to Output in High 7 Delay	CL = 3	Івѕнз	3	Cycle
/	Burst Stop Command to Output in High-Z Delay	CL = 2	I <sub>BSH2</sub>	2	Cycle
8	CAS to CAS Delay (min)		Iccd	1	Cycle
9	CAS Bank Delay (min)		Ісво	1	Cycle

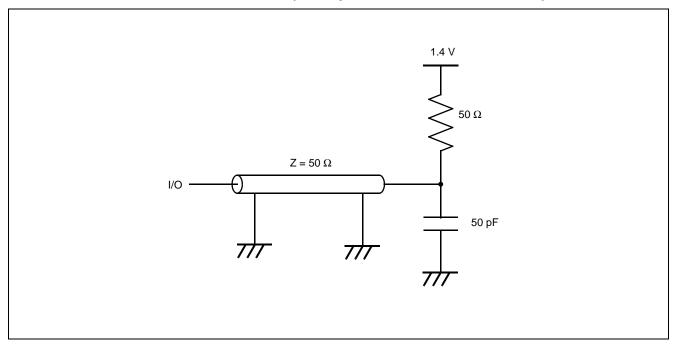
- Notes: \*1. An initial pause (DESL on NOP) of 200 μs is required after power-up followed by a minimum of eight Auto-refresh cycles.
  - \*2. 1.4 V or VREF is the reference level for measuring timing of signals. Transition times are measured between V<sub>IH</sub> (min) and V<sub>IL</sub> (max).
  - \*3. AC characteristics assume  $t_T = 1$  ns and 50 pF of capacitive load.
  - \*4. Maximum value of CL = 2 depends on tck.
  - \*5. tac also specifies the access time at burst mode except for first access.
  - \*6. Specified where output buffer is no longer driven. toH, t∟z, and tHz define the times at which the output level achieves ±200 mV.
  - \*7. Actual clock count of trc (Irc) will be sum of clock count of tras (Iras) and trp (Irp).
  - \*8. Operation within the trop (min) ensures that access time is determined by trop (min) + tac (max); if trop is greater than the specified tRCD (min), access time is determined by tAC.
  - \*9. All base values are measured from the clock edge at the command input to the clock edge for the next command input.

All clock counts are calculated by a simple formula:

clock count equals base value divided by clock period (round off to a whole number).

<sup>\*</sup>Source: See MB81F64842C Data Sheet for details on the electrical.

## ■ AC OPERATING TEST CONDITION (Example of AC Test Load Circuit)



## ■ SERIAL PRESENCE DETECT(SPD) FUNCTION

## 1. PIN DESCRIPTIONS

#### SCL (Serial Clock)

SCL input is used to clock all data input/output of SPD

#### SDA (Serial Data)

SDA is a common pin used for all data input/output of SPD. The SDA pull-up resistor is required due to the open-drain output.

## SA<sub>0</sub>, SA<sub>1</sub>, SA<sub>2</sub> (Address)

Address inputs are used to set the least significant three bits of the eight bits slave address. The address inputs must be fixed to select a particular module and the fixed address of each module must be different each other.

#### 2. SPD OPERATIONS

#### **CLOCK and DATA CONVENTION**

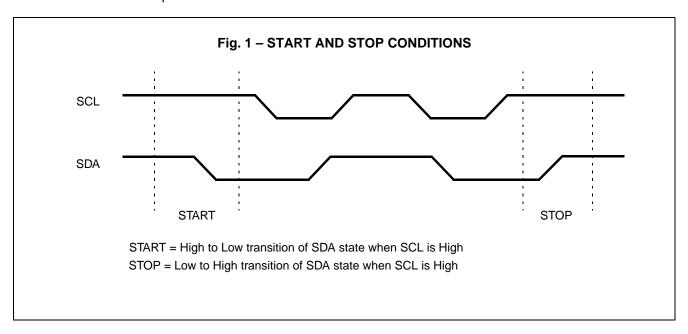
Data states on the SDA can change only during SCL = Low. SDA state changes during SCL = High are indicated start and stop conditions. Refer to Fig. 1 below.

#### START CONDITION

All commands are preceded by a start condition, which is a transition of SDA state from High to Low when SCL = High. SPD will not respond to any command until this condition has been met.

#### STOP CONDITION

All read or write operation must be terminated by a stop condition, which is a transition of SDA state from Low to High when SCL = High. The stop condition is also used to make the SPD into the state of standby power mode after a read sequence.



#### **ACKNOWLEDGE**

Acknowledge is a software convention used to indicate successful data transfer. The transmitting device, either master or slave, will release the bus after transmitting eight bits. During the ninth clock cycle the receiver will put the SDA line to Low in order to acknowledge that it received the eight bits of data.

The SPD will respond with an acknowledge when it received the start condition followed by slave address issued by master.

In the read operation, the SPD will transmit eight bits of data, release the SDA line and monitor the line for an acknowledge. If an acknowledge is detected and no stop condition is issued by master, the SPD will continue to transmit data. If an acknowledge is not detected, the SPD will terminated further data transmissions. The master must then issue a stop condition to return the SPD to the standby power mode.

In the write operation, upon receipt of eight bits of data the SPD will respond with an acknowledge, and await the next eight bits of data, again responding with an acknowledge until the stop condition is issued by master.

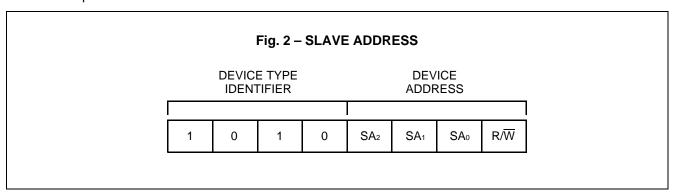
#### **SLAVE ADDRESS ADDRESSING**

Following a start condition, the master must output the eight bits slave address. The most significant four bits of the slave address are device type identifier. For the SPD this is fixed as 1010[B]. Refer to the Fig. 2 below.

The next three significant bits are used to select a particular device. A system could have up to eight SPD devices —namely up to eight modules— on the bus. The eight addresses for eight SPD devices are defined by the state of the  $SA_0$ ,  $SA_1$  and  $SA_2$  inputs.

The last bit of the slave address defines the operation to be performed. When  $R/\overline{W}$  bit is "1", a read operation is selected, when  $R/\overline{W}$  bit is "0", a write operation is selected.

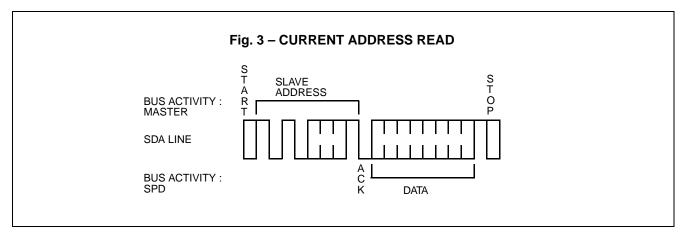
Following the start condition, the SPD monitors the SDA line comparing the slave address being transmitted with its slave address (device type and state of  $SA_0$ ,  $SA_1$ , and  $SA_2$  inputs). Upon a correct compare the SPD outputs an acknowledge on the SDA line. Depending on the state of the  $R/\overline{W}$  bit, the SPD will execute a read or write operation.



#### 3. READ OPERATIONS

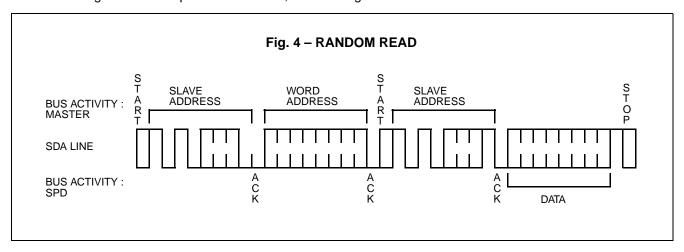
#### **CURRENT ADDRESS READ**

Internally the SPD contains an address counter that maintains the address of the last data accessed, incremented by one. Therefore, if the last access (either a read or write operation) was to address(n), the next read operation would access data from address(n+1). Upon receipt of the slave address with the  $R/\overline{W}$  bit = "1", the SPD issues an acknowledge and transmits the eight bits of data during the next eight clock cycles. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 3 for the sequence of address, acknowledge and data transfer.



#### **RANDOM READ**

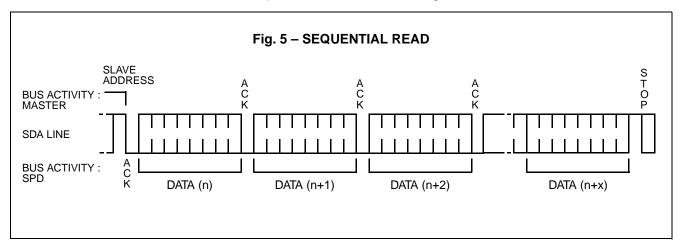
Random Read operations allow the master to access any memory location in a random manner. Prior to issuing the slave address with the  $R/\overline{W}$  bit = "1", the master must first perform a "dummy" write operation on the SPD. The master issues the start condition, and the slave address followed by the word address. After the word address acknowledge, the master immediately reissues the start condition and the slave address with the  $R/\overline{W}$  bit = "1". This will be followed by an acknowledge from the SPD and then by the eight bits of data. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 4 for the sequence of address, acknowledge and data transfer.



#### **SEQUENTIAL READ**

Sequential Read can be initiated as either a current address read or random read. The first data are transmitted as with the other read mode, however, the master now responds with an acknowledge, indicating it requires additional data. The SPD continues to output data for each acknowledge received. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 5 for the sequence of address, acknowledge and data transfer.

The data output is sequential, with the data from address(n) followed by the data from address(n+1). The address counter for read operations increments all address bits, allowing the entire memory contents to be serially read during one operation. At the end of the address space (address 255), the counter "rolls over" to address 0 and the SPD continues to output data for each acknowledge received.



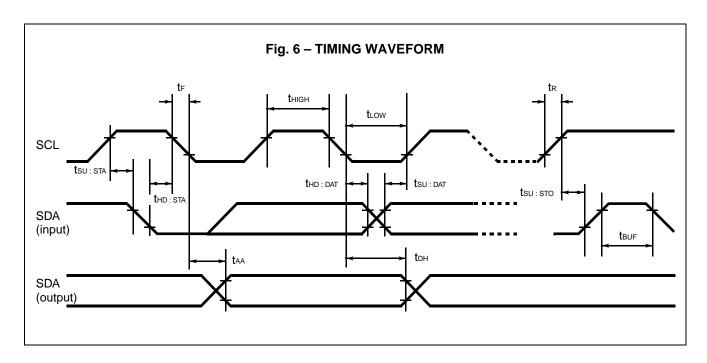
## 4. DC CHARACTERISTICS

Parameter	Note	Symbol	Condition	Va	Unit	
Parameter				Min.	Max.	
Input Leakage Current		Sılı	$0 \text{ V} \leq V_{IN} \leq V_{CC}$	-10	10	μΑ
Output Leakage Current		SILO	0 V ≤ Vouт ≤ Vcc	-10	10	μΑ
Output Low Voltage	*1	Svol	IoL = 3.0 mA	_	0.4	V

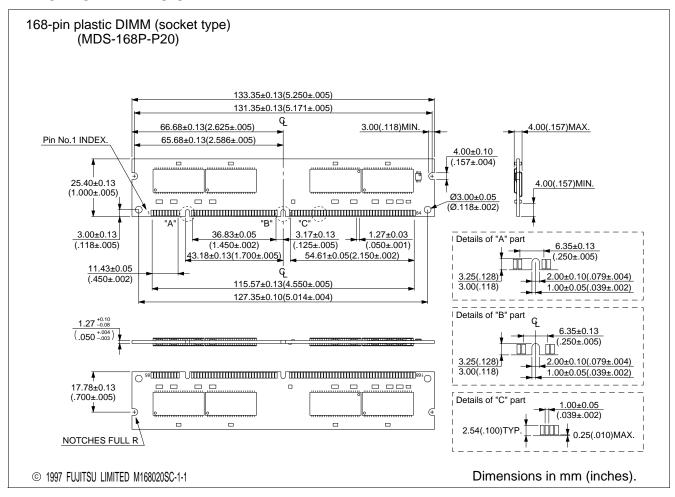
Note: \*1. Referenced to Vss.

## 5. AC CHARACTERISTICS

No.	Parameter	Comple of	Value		I I m i 4
		Symbol	Min.	Max.	Unit
1	SCL Clock Frequency	fsc∟	_	100	KHz
2	Noise Suppression Time Constant at SCL, SDA Inputs	Tı	_	100	ns
3	SCL Low to SDA Data Out Valid	<b>t</b> AA	_	3.5	μs
4	Time the Bus Must Be Free Before a New Transmission Can Start	<b>t</b> BUF	4.7	_	μs
5	Start Condition Hold Time	<b>t</b> hd:sta	4.0	_	μs
6	Clock Low Period	tLOW	4.7	_	μs
7	Clock High Period	tніgн	4.0	_	μs
8	Start Condition Setup Time	tsu:sta	4.7	_	μs
9	Data in Hold Time	<b>t</b> hd:dat	0	_	μs
10	Data in Setup Time	tsu:dat	250	_	ns
11	SDA and SCL Rise Time	t <sub>R</sub>	_	1	μs
12	SDA and SCL Fall Time	t⊧	_	300	ns
13	Stop Condition Setup Time	tsu:sto	4.7	_	μs
14	Data Out Hold Time	tон	100	_	ns
15	Write Cycle Time	twr	_	15	ms



## **■ PACKAGE DIMENSION**



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